## Notice of References Cited Application/Control No. 10/724,630 Examiner Disler Paul Applicant(s)/Patent Under Reexamination CHEN, WAN-TIEN Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	. А	US-2002/0074953 A1	06-2002	Lovell et al.	315/248
*	В	US-2002/0172380 A1	11-2002	Girard, Nicolas	381/120
*	С	US-2003/0001715 A1	01-2003	Montague, William A.	337/198
*	D	US-2003/0117805 A1	06-2003	Pasternak et al.	362/429
*	Е	US-2003/0228025 A1	12-2003	Hannah, Eric C.	381/113
*	F	US-2004/0132337 A1	07-2004	Plishner, Paul J.	439/577
*	G	US-2005/0213775 A1	09-2005	Wong, Ming-Yuan	381/077
	Н	US-			·
	-	US-			
	J	US-			
	Κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	x	

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